## Notice of References Cited

Application/Control No.

10/579,223

Examiner

Karl J. Puttlitz

Applicant(s)/Patent Under
Reexamination
DE FERRA ET AL.

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## **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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